

## **AMENDMENTS TO THE SPECIFICATION:**

Please replace the paragraph beginning at page 1, line 19, with the following rewritten paragraph:

- 1           As an example, an integrated circuit ~~a specific ASP-Wireless device~~
- 2     containing an Analog to Digital Converter (ADC) typically requires test
- 3     verification. The test verification of two key parameters F(full scale)set and
- 4     Z(zero)set is usually considered ~~are critical in such cases~~. Unfortunately, contact
- 5     resistance during bump probing is often too high to correctly validate the
- 6     operation of the ADC for these two parameters.